

### IN THE CLAIMS

Please amend the claims as follows:

1. (Currently Amended) A method, comprising:  
storing at least one input operating over-voltage condition occurring in an integrated circuit in an indelible memory.
2. (Original) The method of claim 1, further comprising:  
determining a specified number of stored over-voltage conditions.
3. (Original) The method of claim 2, further comprising:  
indicating the specified number of stored over-voltage conditions.
4. (Currently Amended) A method, comprising:  
comparing an input operational condition with a specified condition;  
recording an out-of-specification input operating condition in an indelible memory; and  
determining a specified number of recorded out-of-specification input operating conditions.
5. (Currently Amended) The method of claim 4, further comprising:  
detecting the out-of-specification input operating condition as an input operating over-voltage condition.
6. (Currently Amended) The method of claim 4, further comprising:  
refraining from detecting the out-of-specification input operating condition for a specified amount of time.

7. (Original) The method of claim 6, wherein the specified amount of time is associated with a power-on reset time.
8. (Currently Amended) The method of claim 4, wherein the specified condition comprises a recommended operational input voltage upper limit associated with an integrated circuit.
9. (Currently Amended) The method of claim 4, wherein recording the out-of-specification input operating condition further comprises:  
recording a clock speed as ~~the out-of-specification condition~~.
10. (Previously Presented) The method of claim 9, wherein the indelible memory comprises at least one fuse.
11. (Currently Amended) The method of claim 4, wherein determining the specified number of recorded out-of-specification input operating conditions further comprises:  
reading a signature value stored in the indelible memory.
12. (Currently Amended) An article comprising a machine-accessible medium having associated data, wherein the data, when accessed, results in a machine performing:  
comparing an input operational voltage with a specified voltage;  
recording an input operating over-voltage condition in an indelible memory; and  
determining a specified number of recorded over-voltage conditions.
13. (Currently Amended) The article of claim 12, wherein the data, when accessed, results in the machine performing:  
filtering the input operational voltage for at least a duration of one clock period.
14. (Currently Amended) The article of claim 12, wherein recording the input operating over-voltage condition further comprises:

recording the input operating over-voltage condition only if the input operational voltage is greater than the specified voltage by a selected amount.

15. (Original) The article of claim 14, wherein the selected amount is at least about two times greater than an expected noise voltage value.

16. (Currently Amended) The article of claim 12, wherein the data, when accessed, results in the machine performing:  
verifying recordation of the input operating over-voltage condition.

17. (Currently Amended) An apparatus, comprising:  
an indelible memory to store a selected number of out-of-specification input operational conditions encountered by an electronic circuit.

18. (Currently Amended) The apparatus of claim 17, further comprising:  
a detection module coupled to the indelible memory to determine the existence of at least one of the selected number of out-of-specification input operational conditions.

19. (Original) The apparatus of claim 18, further comprising:  
a filter module coupled to the detection module.

20. (Original) The apparatus of claim 17, wherein the indelible memory comprises a fuse.

21. (Currently Amended) The apparatus of claim 17, wherein at least one of the out-of-specification input operational conditions comprises an over-voltage condition.

22. (Currently Amended) A system, comprising:  
an indelible memory to store a selected number of out-of-specification input operational conditions encountered by an electronic circuit; and  
a display coupled to the electronic circuit.

23. (Original) The system of claim 22, wherein the electronic circuit comprises a microprocessor.
24. (Currently Amended) The system of claim 22, further comprising:  
a logic module to detect each one of the selected number of out-of-specification input operational conditions.
25. (Original) The system of claim 24, wherein the logic module comprises an analog-to-digital converter.
26. (Original) The system of claim 22, further comprising:  
a memory to store a specified condition to be compared with an operational condition associated with the electronic circuit.
27. (Currently Amended) The system of claim 26, wherein the specified condition comprises a recommended operational input voltage upper limit associated with an integrated circuit.
28. (Original) The system of claim 27, wherein the integrated circuit comprises a microprocessor.
29. (Currently Amended) The system of claim 22, further comprising:  
a basic input-output system to determine the selected number of out-of-specification input operational conditions.